

March 2013

## **FCD380N60E**

# N-Channel SuperFET® II MOSFET

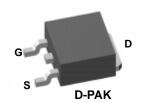
600 V, 10.2 A, 380 mΩ

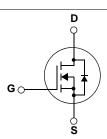
### **Features**

- 650 V @T<sub>J</sub> = 150°C
- Max.  $R_{DS(on)} = 380 \text{ m}\Omega$
- Ultra Low Gate Charge (Typ. Q<sub>g</sub> = 34 nC)
- Low Effective Output Capacitance (Typ. Coss.eff = 97 pF)
- 100% Avalanche Tested

## **Description**

SuperFET<sup>®</sup>II MOSFET is Fairchild Semiconductor<sup>®</sup>'s first generation of high voltage super-junction (SJ) MOSFET family that is utilizing charge balance technology for outstanding low on-resistance and lower gate charge performance. This advanced technology is tailored to minimize conduction loss, provide superior switching performance, and withstand extreme dv/dt rate and higher avalanche energy. Consequently, SuperFETII MOSFET is suitable for various AC/DC power conversion for system miniaturization and higher efficiency.





## MOSFET Maximum Ratings T<sub>C</sub> = 25°C unless otherwise noted

Symbol		Parameter		FCD380N60E	Unit
V <sub>DSS</sub>	Drain to Source Voltage			600	V
V	Cata to Source Voltage	- DC		±20	V
V <sub>GSS</sub> Gate to Source Voltage	- AC	(f > 1 Hz)	±30	V	
1	Drain Current	-Continuous (T <sub>C</sub> = 25°C)		10.2	^
I <sub>D</sub>	Drain Current	-Continuous (T <sub>C</sub> = 100°C)		6.4	Α
I <sub>DM</sub>	Drain Current	- Pulsed	(Note 1)	30.6	Α
E <sub>AS</sub>	Single Pulsed Avalanche En	ergy	(Note 2)	211.6	mJ
I <sub>AR</sub>	Avalanche Current		(Note 1)	2.3	Α
E <sub>AR</sub>	Repetitive Avalanche Energy	1	(Note 1)	1.06	mJ
dv/dt	Peak Diode Recovery dv/dt		(Note 3)	20	V/ns
uv/ui	MOSFET dv/dt			100	V/115
D	Power Dissipation	(T <sub>C</sub> = 25°C)		106	W
$P_{D}$	Power Dissipation	- Derate above 25°C		0.85	W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temp	perature Range		-55 to +150	°C
T <sub>L</sub>	Maximum Lead Temperature 1/8" from Case for 5 Second	• • •		300	°C

<sup>\*</sup>Drain current limited by maximum junction temperature

## **Thermal Characteristics**

Symbol	Parameter	FCD380N60E	Unit
$R_{\theta JC}$	Thermal Resistance, Junction to Case	1.18	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	100	*C/VV

## **Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FCD380N60E	FCD380N60E	D-PAK	380 mm	16 mm	2500

## **Electrical Characteristics** $T_C = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter	lest Conditions	Min.	iyp.	Max.	Unit
Off Chara	cteristics					
B\/	Drain to Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 10 \text{ mA}, T_J = 25^{\circ}\text{C}$	600	-	-	V
BV <sub>DSS</sub>	Dialii to Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 10 \text{ mA}, T_J = 150^{\circ}\text{C}$	650	-	-	V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 10 mA, Referenced to 25°C	-	0.67	-	V/°C
BV <sub>DS</sub>	Drain-Source Avalanche Breakdown Voltage	V <sub>GS</sub> = 0 V, I <sub>D</sub> = 10 A	-	700	-	V
1	Zero Gate Voltage Drain Current	$V_{DS} = 480 \text{ V}, V_{GS} = 0 \text{ V}$	-	-	5	пΔ
IDSS	Zero Gate voltage Drain Guirent	$V_{DS} = 480 \text{ V}, T_{C} = 125^{\circ}\text{C}$	-	-	20	μΑ
I <sub>GSS</sub>	Gate to Body Leakage Current	$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$	-	-	±100	nA

## **On Characteristics**

V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$	2.5	-	3.5	V
R <sub>DS(on)</sub>	Static Drain to Source On Resistance	$V_{GS} = 10 \text{ V}, I_D = 5 \text{ A}$	-	0.32	0.38	Ω
g <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = 20 V, I <sub>D</sub> = 5 A	-	10	-	S

## **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	V 25.V.V 2.V	=	1330	1770	pF
C <sub>oss</sub>		V <sub>DS</sub> = 25 V, V <sub>GS</sub> = 0 V		945	1260	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1 – 1 101112	-	60	90	pF
C <sub>oss</sub>	Output Capacitance	$V_{DS} = 380 \text{ V}, V_{GS} = 0 \text{V}, f = 1.0 \text{ MHz}$	-	25	-	pF
Coss eff.	Effective Output Capacitance	V <sub>DS</sub> = 0 V to 480 V, V <sub>GS</sub> = 0 V	-	97	-	pF
Q <sub>g(tot)</sub>	Total Gate Charge at 10V		-	34	45	nC
$Q_{gs}$		$V_{DS} = 380 \text{ V}, I_{D} = 5 \text{ A}$	-	5.3	ı	nC
Q <sub>gd</sub>	Gate to Drain "Miller" Charge	$V_{GS} = 10 \text{ V}$ (Note 4)	-	13	1	nC
ESR	Equivalent Series Resistance	Drain open	-	6	-	Ω

## **Switching Characteristics**

t <sub>d(on)</sub>	Turn-On Delay Time			=	17	44	ns
t <sub>r</sub>	Turn-On Rise Time	$V_{DD} = 380 \text{ V}, I_{D} = 5 \text{ A}$		-	9	28	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$V_{GS} = 10 \text{ V}, R_G = 4.7 \Omega$		-	64	138	ns
t <sub>f</sub>	Turn-Off Fall Time		(Note 4)	-	10	30	ns

## **Drain-Source Diode Characteristics**

I <sub>S</sub>	Maximum Continuous Drain to Source Diode Forward Current			-	10.2	Α
$I_{SM}$	Maximum Pulsed Drain to Source Diode Forward Current		-	-	30.6	Α
$V_{SD}$	Drain to Source Diode Forward Voltage V <sub>GS</sub> = 0V, I <sub>SD</sub> = 5 A		-	-	1.2	V
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> = 0V, I <sub>SD</sub> = 5 A	-	240	-	ns
Q <sub>rr</sub>	Reverse Recovery Charge	$dI_F/dt = 100 A/\mu s$	-	3	-	μС

#### Notes

- ${\bf 1.}\ {\bf Repetitive}\ {\bf Rating:}\ {\bf Pulse}\ {\bf width}\ {\bf limited}\ {\bf by}\ {\bf maximum}\ {\bf junction}\ {\bf temperature}$
- 2.  $I_{AS}$  = 2.3 A,  $V_{DD}$  = 50 V,  $R_{G}$  = 25  $\Omega,$  Starting  $T_{J}$  = 25°C
- 3. I  $_{SD} \leq$  5.1 A, di/dt  $\leq$  200 A/µs, V  $_{DD} \leq$  BV  $_{DSS}$ , Starting T  $_{J}$  = 25°C
- 4. Essentially Independent of Operating Temperature Typical Characteristics

## **Typical Performance Characteristics**

Figure 1. On-Region Characteristics

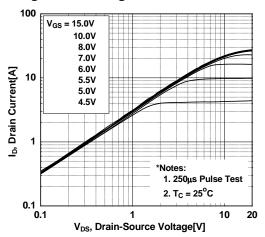


Figure 3. On-Resistance Variation vs.
Drain Current and Gate Voltage

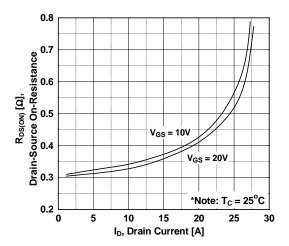
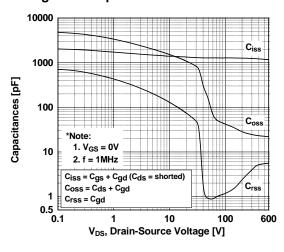


Figure 5. Capacitance Characteristics



**Figure 2. Transfer Characteristics** 

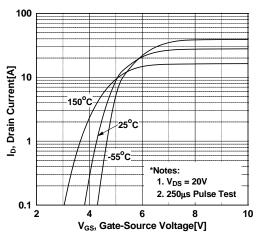


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

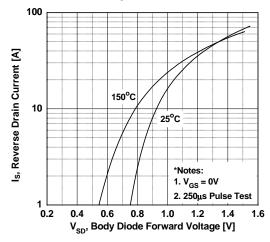
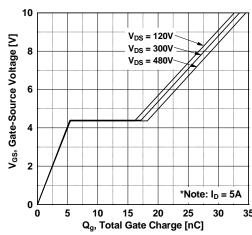


Figure 6. Gate Charge Characteristics



## **Typical Performance Characteristics (Continued)**

Figure 7. Breakdown Voltage Variation vs. Temperature

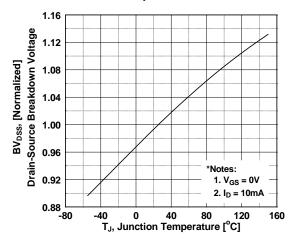


Figure 9. Maximum Safe Operating Area vs. Case Temperature

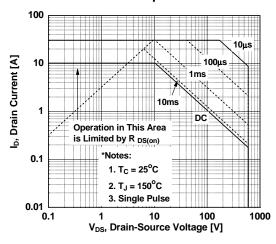


Figure 8. On-Resistance Variation vs. Temperature

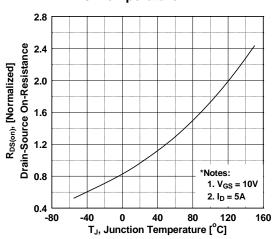


Figure 10. Maximum Drain Current

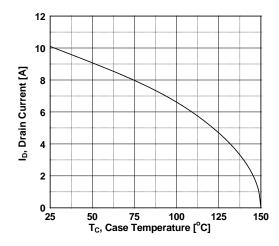
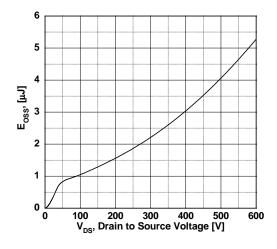
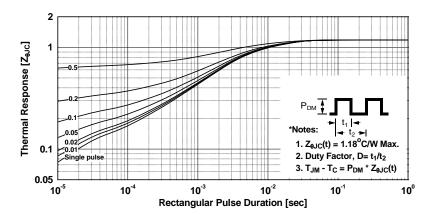


Figure 11. Eoss vs. Drain to Source Voltage Switching Capability

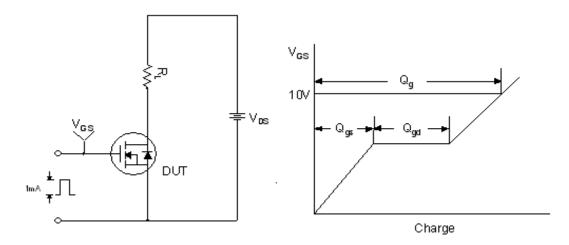


## **Typical Performance Characteristics** (Continued)

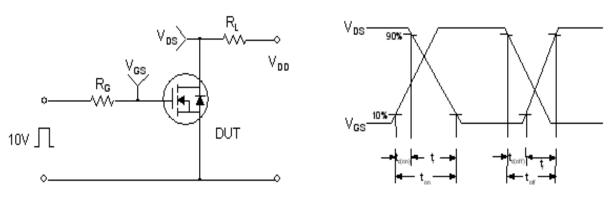
Figure 12. Transient Thermal Response Curve



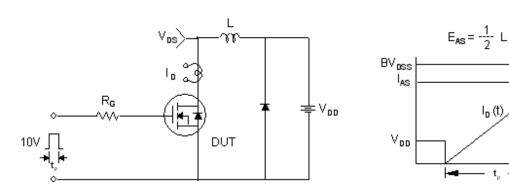
## **Gate Charge Test Circuit & Waveform**



## **Resistive Switching Test Circuit & Waveforms**

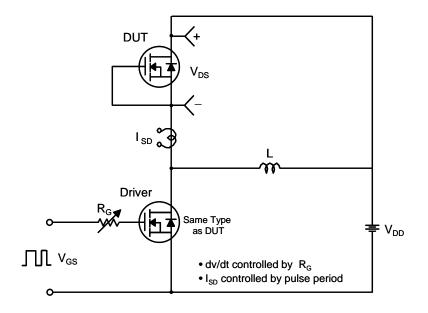


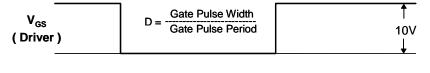
## **Unclamped Inductive Switching Test Circuit & Waveforms**

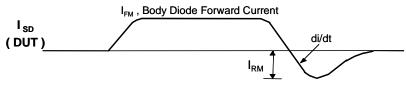


V<sub>os</sub>(t) Time

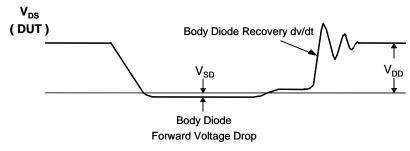
## Peak Diode Recovery dv/dt Test Circuit & Waveforms





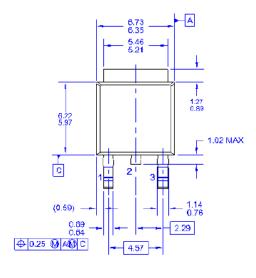


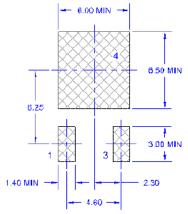
Body Diode Reverse Current



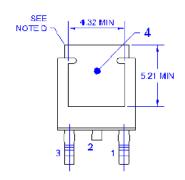
## **Mechanical Dimensions**

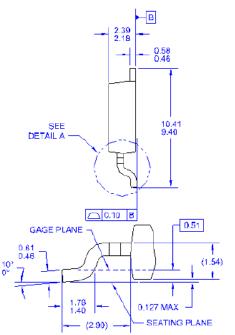
## **D-PAK**





## LAND PATTERN RECOMMENDATION





- NOTES: LINLESS OTHERWISE SPECIFIED

  A) THIS PACKAGE CONFORMS TO JEDEC, TO-252.
  ISSUE C, VARIATION AA.

  B) ALL DINEMSIONS ARE IN MILLIMETERS.
  C) DINEMSIONING AND TOLEMANCING PER
  ASME Y14.5M-1994.
  D) HEAT SINK TOP EDGE COULD BE IN CHAMFERED
  CORNERS OR EDGE FROTRUSION.
  E) PRESENCE OF TRIMMED CENTER LEAD
  IS OPTIONAL
  F) DIMENSIONS ARE EXCLUSRIVE OF BURSS,
  MOLD FLASH AND THE BAR EXTRUSIONS.
  B) LAND PATTERN RECOMENDATION IS BASED ON IPC7351A STD
  TO220P1003X295-3N.
- TO220P1009X239-3N.
  H: DRAWING NUMBER AND REVISION: WKT-TO252A03REVB

**Dimensions in Millimeters** 





#### **TRADEMARKS**

The following includes registered and unregistered trademarks and service marks, owned by Fairchild Semiconductor and/or its global subsidiaries, and is not intended to be an exhaustive list of all such trademarks.

2Cool™ F-PFS™ AccuPower™ FRFET® AX-CAP<sup>TM</sup>
BitSiC<sup>®</sup> Global Power Resource<sup>SM</sup> Green Bridge™ Build it Now™ Green FPS™ CorePLUS™ Green FPS™ e-Series™ CorePOWER™  $\mathsf{G} max^{\mathsf{TM}}$  $\mathsf{GTO}^{\mathsf{TM}}$  $CROSSVOLT^{TM}$ IntelliMAX™

ISOPLANAR™ Current Transfer Logic™ Marking Small Speakers Sound Louder DEUXPEED®

Dual Cool™ and Better™ EcoSPARK® MegaBuck™ EfficentMax™ MICROCOUPLER™ ESBC™

MicroFET™ MicroPak™ MicroPak2™ MillerDrive™ Fairchild® MotionMax™ Fairchild Semiconductor® FACT Quiet Series™ FACT® FAST® Motion-SPM™ mWSaver™ OptoHiT™ **OPTOLOGIC®** FastvCore™

FETBench™ FlashWriter® \* PowerTrench<sup>®</sup> PowerXS<sup>TM</sup>

Programmable Active Droop™

QFET<sup>®</sup>  $QS^{TM}$ Quiet Series™ RapidConfigure™

Saving our world, 1mW/W/kW at a time™

SignalWise™ SmartMax™ SMART START™

Solutions for Your Success™

STEALTH™ SuperFET® SuperSOT™-3 SuperSOT™-6 SuperSOT™-8 SupreMOS® SyncFET™ Sync-Lock™

SYSTEM ® GENERAL

The Power Franchise®

bwer franchise TinyBoost™ TinyBuck™ TinyCalc™ TinyLogic<sup>®</sup> TINYOPTO™ TinyPower™ TinyPWM™ TinyWire™ TranSiC® TriFault Detect™ TRUECURRENT®\*

**UHC®** Ultra FRFET™ UniFET™ VCX<sup>TM</sup> VisualMax™ VoltagePlus™ XS™

\*Trademarks of System General Corporation, used under license by Fairchild Semiconductor.

OPTOPLANAR®

PRODUCT OR CIRCUIT DESCRIBED HEREIN; NEITHER DOES IT CONVEY ANY LICENSE UNDER ITS PATENT RIGHTS, NOR THE RIGHTS OF OTHERS. THESE SPECIFICATIONS DO NOT EXPAND THE TERMS OF FAIRCHILD'S WORLDWIDE TERMS AND CONDITIONS, SPECIFICALLY THE WARRANTY THEREIN, WHICH COVERS THESE DUCTS.

**LIFE SUPPORT POLICY**FAIRCHILD'S PRODUCTS ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS WITHOUT THE EXPRESS WRITTEN APPROVAL OF FAIRCHILD SEMICONDUCTOR CORPORATION.

As used here in:

- Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body or (b) support or sustain life, and (c) whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in a significant injury of the user.
- A critical component in any component of a life support, device, or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

#### ANTI-COUNTERFEITING POLICY

Fairchild Semiconductor Corporation's Anti-Counterfeiting Policy. Fairchild's Anti-Counterfeiting Policy is also stated on our external website, www.Fairchildsemi.com, under Sales Support.

Counterfeiting of semiconductor parts is a growing problem in the industry. All manufactures of semiconductor products are experiencing counterfeiting of their

parts. Customers who inadvertently purchase counterfeit parts experience many problems such as loss of brand reputation, substandard performance, falled application, and increased cost of production and manufacturing delays. Fairchild is taking strong measures to protect ourselves and our customers from the application, and increased cost of production and manufacturing delays. Fairchild is taking strong measures to protect ourselves and our customers from the proliferation of counterfeit parts. Fairchild strongly encourages customers to purchase Fairchild parts either directly from Fairchild or from Authorized Fairchild Distributors who are listed by country on our web page cited above. Products customers buy either from Fairchild directly or from Authorized Fairchild Distributors are genuine parts, have full traceability, meet Fairchild's quality standards for handing and storage and provide access to Fairchild's full range of up-to-date technical and product information. Fairchild and our Authorized Distributors will stand behind all warranties and will appropriately address and warranty issues that may arise. Fairchild will not provide any warranty coverage or other assistance for parts bought from Unauthorized Sources. Fairchild is committed to combat this global problem and encourage our customers to do their part in stopping this practice by buying direct or from authorized distributors.

#### PRODUCT STATUS DEFINITIONS **Definition of Terms**

Datasheet Identification	Product Status	Definition
Advance Information	Formative / In Design	Datasheet contains the design specifications for product development. Specifications may change in any manner without notice.
Preliminary	First Production	Datasheet contains preliminary data; supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve design.
No Identification Needed	Full Production	Datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve the design.
Obsolete	Not In Production	Datasheet contains specifications on a product that is discontinued by Fairchild Semiconductor. The datasheet is for reference information only.

Rev. 161